Search Notes						

Application/Control No.	Applicant(s)/Patent und Reexamination	er
09/755,207	CHEN ET AL.	
Examiner	Art Unit	
Tu V Nauvon	2618	

SEARCHED				
Class	Subclass	Date	Examiner	
455	437	11/7/2006	TN	
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Subclass	D-4-	
	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Search East	11/7/2006	TN	
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